

**Search Notes**

Application/Control No.

10/619,162

Examiner

Harold Kim

Applicant(s)/Patent under  
Reexamination

HAYDEN ET AL.

Art Unit

2182

**SEARCHED**

Class	Subclass	Date	Examiner
710	5, 29, 36, 52, 7, 100, 118	6/22/2005	HK
711	138, 225	6/22/2005	HK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, USPGPUB, JPO, EPO, IEEE, NPL, see attached search note, inventor search on eDAN	6/22/2005	HK